

C3M0045065K

Silicon Carbide Power MOSFET C3M MOSFET Technology

N-Channel Enhancement Mode

Features

- C3M™ SiC MOSFET technology
- Optimized package with separate driver source pin
- 8mm of creepage distance between drain and source
- High blocking voltage with low on-resistance
- High-speed switching with low capacitances
- Fast intrinsic diode with low reverse recovery (Q,,)
- Halogen free, RoHS compliant

Benefits

- Reduce switching losses and minimize gate ringing
- Higher system efficiency
- Reduce cooling requirements
- Increase power density
- Increase system switching frequency

Applications

- EV chargers
- Server & Telecom PSU
- **UPS**
- Solar inverters
- **SMPS**
- DC/DC converters

$\mathbf{V}_{\mathtt{DS}}$	650 V
I _D @ 25°C	49 A
	45

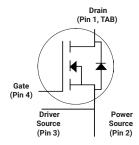
 $45 \, \text{m}\Omega$ R_{DS(on)}

Package









Part Number	Package	Marking
C3M0045065K	TO 247-4	C3M0045065K

Maximum Ratings

Symbol	Parameter	Value	Unit	Note
V _{DSS}	Drain - Source Voltage, T _C = 25 °C	650	٧	
V_{GS}	Gate - Source voltage (Under transient events < 100 ns)	-8/+19	٧	Fig. 29
	Continuous Drain Current, V _{GS} = 15 V, T _C = 25°C			
l _D	Continuous Drain Current, V _{GS} = 15 V, T _C = 100°C	35	Α	Fig. 19
I _{D(pulse)}	Pulsed Drain Current, Pulse width t _P limited by T _{jmax}		Α	
P _D	Power Dissipation, $T_c=25^{\circ}C$, $T_J=175^{\circ}C$		W	Fig. 20
T _J , T _{stg}	Operating Junction and Storage Temperature		°C	
T _L	Solder Temperature, 1.6mm (0.063") from case for 10s		°C	
M_d	Mounting Torque, (M3 or 6-32 screw)	1 8.8	Nm lbf-in	



Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Conditions	Note
V _{(BR)DSS}	Drain-Source Breakdown Voltage	650			٧	V _{GS} = 0 V, I _D = 100 μA	
V_{GSon}	Gate-Source Recommended Turn-On Voltage		15		V	Statio	Fig. 20
V_{GSoff}	Gate-Source Recommended Turn-Off Voltage		-4		V	Static	Fig. 29
V	Gate Threshold Voltage	1.8	2.6	3.6	V	V _{DS} = V _{GS} , I _D = 4.84 mA	Fig. 11
$V_{GS(th)}$	Gate Threshold Voltage		2.2		V	$V_{DS} = V_{GS}$, $I_D = 4.84$ mA, $T_J = 175$ °C	
I _{DSS}	Zero Gate Voltage Drain Current		1	50	μΑ	V _{DS} = 650 V, V _{GS} = 0 V	
I _{GSS}	Gate-Source Leakage Current		10	250	nA	V _{GS} = 15 V, V _{DS} = 0 V	
R _{DS(on)}	Drain-Source On-State Resistance		45	60	mΩ	V _{GS} = 15 V, I _D = 17.6 A	Fig. 4,
* DS(on)	Draw course on state resistance		61			V _{GS} = 15 V, I _D = 17.6 A, T _J = 175°C	5,6
g _{fs}	Transconductance		12		S	V _{DS} = 20 V, I _{DS} = 17.6 A	Fig. 7
9 18	Transconductance		11		Ŭ	V _{DS} = 20 V, I _{DS} = 17.6 A, T _J = 175°C	1 19. 7
C_{iss}	Input Capacitance		1621			$V_{GS} = 0 \text{ V, } V_{DS} = 0 \text{ V to } 600 \text{ V}$	
C_{oss}	Output Capacitance		101			F = 1 Mhz	Fig. 17, 18
C _{rss}	Reverse Transfer Capacitance		8		pF	Vac = 25 mV	10
$C_{o(er)}$	Effective Output Capacitance (Energy Related)		126				Note: 1
C _{o(tr)}	Effective Output Capacitance (Time Related)		178		1	$V_{GS} = 0 \text{ V, } V_{DS} = 0 \text{V to } 400 \text{ V}$	Note: 1
E _{oss}	C _{oss} Stored Energy		20		μJ	V _{DS} = 600 V, F = 1 Mhz	Fig. 16
Eon	Turn-On Switching Energy (Body Diode)		57			$V_{DS} = 400 \text{ V}, V_{GS} = -4 \text{ V}/15 \text{ V}, I_{D} = 17.6 \text{ A},$	
E _{OFF}	Turn Off Switching Energy (Body Diode)		14		μJ	$R_{G(ext)}$ = 2.5 Ω, L= 99 μH, T_J = 175°C FWD = Internal Body Diode of MOSFET	Fig. 25
Eon	Turn-On Switching Energy (External Diode)		44			$V_{DS} = 400 \text{ V}, V_{GS} = -4 \text{ V}/15 \text{ V}, I_{D} = 17.6 \text{ A},$	
E _{OFF}	Turn Off Switching Energy (External Diode)		14		μJ	$R_{G(ext)}$ = 2.5 Ω, L= 99 μH, T_J = 175°C FWD = External SiC DIODE	Fig. 25
t _{d(on)}	Turn-On Delay Time		9				
t _r	Rise Time		12]	V_{DD} = 400 V, V_{GS} = -4 V/15 V I_D = 17.6 A, $R_{G(ext)}$ = 2.5 Ω, L= 99 μH Timing relative to V_{DS} Inductive load	Fig. 26
$t_{\text{d(off)}}$	Turn-Off Delay Time		18		ns		
t _f	Fall Time		6			Inductive load	
$R_{G(int)}$	Internal Gate Resistance		3		Ω	f = 1 MHz, V _{AC} = 25 mV	
Q_{gs}	Gate to Source Charge		21			V _{DS} = 400 V, V _{GS} = -4 V/15 V	
Q_{gd}	Gate to Drain Charge		18	18 nC $I_D = 17.6 A$	I _D = 17.6 A	Fig. 12	
Q_g	Total Gate Charge		63			Per IEC60747-8-4 pg 21	

Note (1): $C_{o(er)}$, a lumped capacitance that gives same stored energy as Coss while Vds is rising from 0 to 400V $C_{o(tr)}$, a lumped capacitance that gives same charging time as Coss while Vds is rising from 0 to 400V



Reverse Diode Characteristics ($T_c = 25^{\circ}C$ unless otherwise specified)

Symbol	Parameter	Тур.	Max.	Unit	Test Conditions	Note
V _{SD}	V Diede Fermand Voltage	4.8		٧	V _{GS} = -4 V, I _{SD} = 8.8 A, T _J = 25 °C	Fig. 8,
V SD	Diode Forward Voltage	4.2		٧	V _{GS} = -4 V, I _{SD} = 8.8 A, T _J = 175 °C	9,10
Is	Continuous Diode Forward Current		29	Α	$V_{GS} = -4 \text{ V, } T_C = 25^{\circ}\text{C}$	
I _{S, pulse}	Diode pulse Current		132	Α	$V_{GS} = -4 \text{ V}$, pulse width t_P limited by T_{jmax}	
t _{rr}	Reverse Recover time	13		ns		
Q _{rr}	Reverse Recovery Charge	247		nC	V _{gS} = -4 V, I _{SD} = 17.6 A, V _R = 400 V dif/dt = 5215 A/μs, T _J = 175 °C	
I _{rrm}	Peak Reverse Recovery Current	36		Α		
t _{rr}	Reverse Recover time	18		ns		
Q _{rr}	Reverse Recovery Charge	171		nC	V _{GS} = -4 V, I _{SD} = 17.6 A, V _R = 400 V dif/dt = 1775 A/μs, Τ _Ι = 175 °C	
I _{rrm}	Peak Reverse Recovery Current	16		А		

Thermal Characteristics

Symbol	Parameter	Тур.	Unit	Test Conditions	Note
R _{θJC}	Thermal Resistance from Junction to Case	0.85	°C/W		Fig. 21
R _{0JA}	Thermal Resistance From Junction to Ambient	40	C/VV		Fig. 21



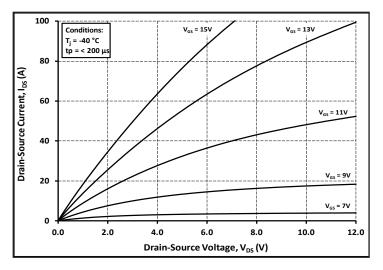
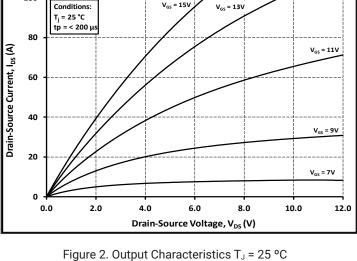


Figure 1. Output Characteristics T_J = -40 °C



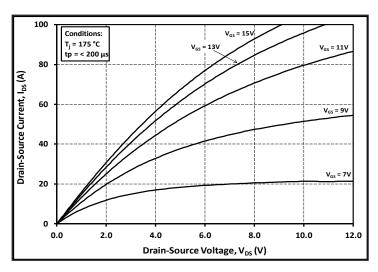


Figure 3. Output Characteristics T_J = 175 °C

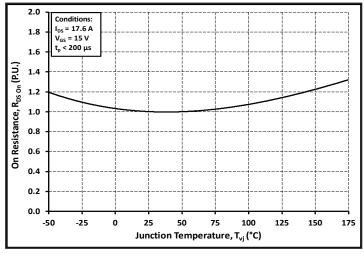


Figure 4. Normalized On-Resistance vs. Temperature

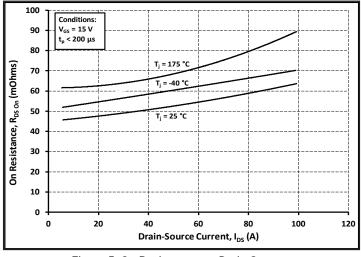


Figure 5. On-Resistance vs. Drain Current For Various Temperatures

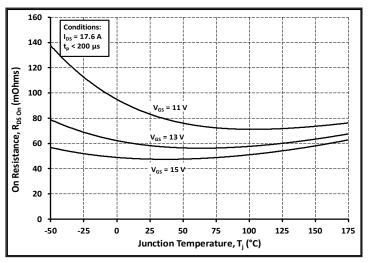
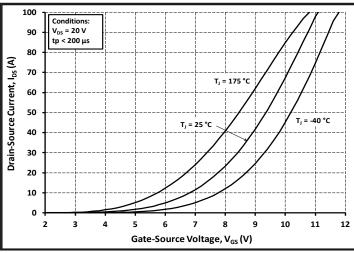


Figure 6. On-Resistance vs. Temperature For Various Gate Voltage







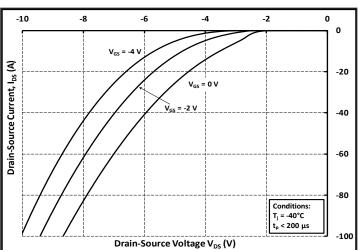


Figure 8. Body Diode Characteristic at -40 °C

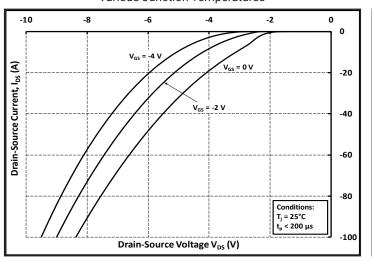


Figure 9. Body Diode Characteristic at 25 °C

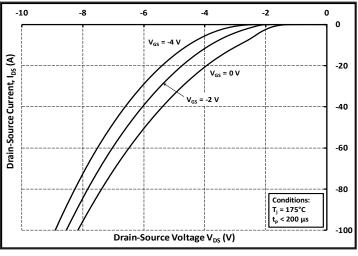


Figure 10. Body Diode Characteristic at 175 °C

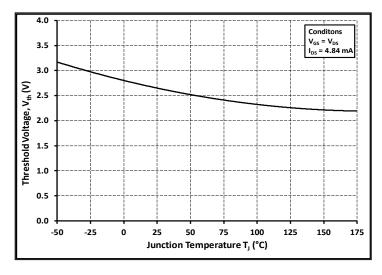


Figure 11. Threshold Voltage vs. Temperature

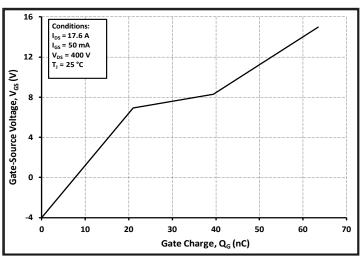


Figure 12. Gate Charge Characteristics



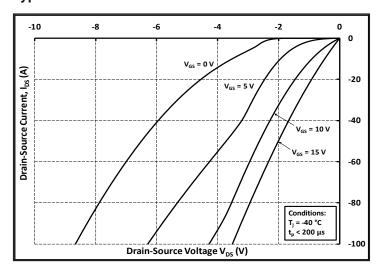


Figure 13. 3rd Quadrant Characteristic at -40 °C

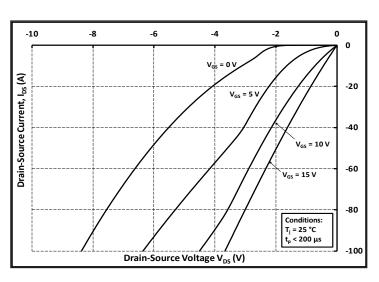


Figure 14. 3rd Quadrant Characteristic at 25 °C

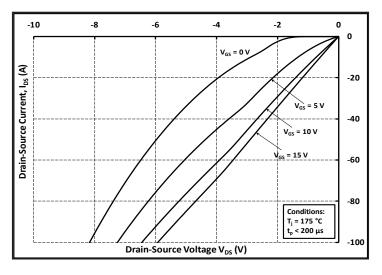


Figure 15. 3rd Quadrant Characteristic at 175 °C

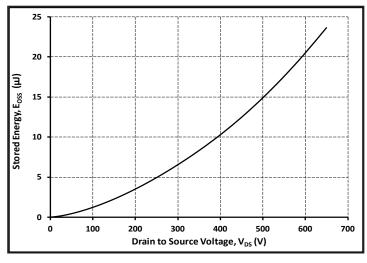


Figure 16. Output Capacitor Stored Energy

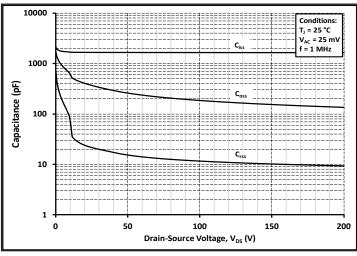


Figure 17. Capacitances vs. Drain-Source Voltage (0 - 200V)

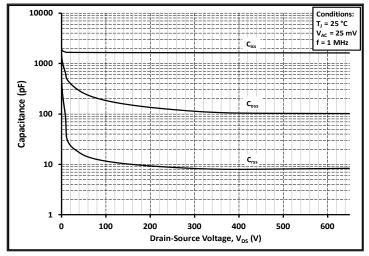


Figure 18. Capacitances vs. Drain-Source Voltage (0 - 650V)



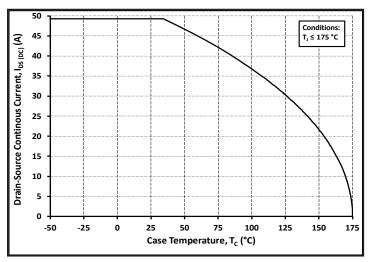


Figure 19. Continuous Drain Current Derating vs.

Case Temperature

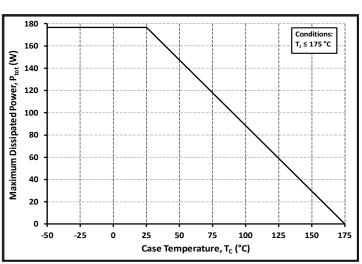


Figure 20. Maximum Power Dissipation Derating vs.

Case Temperature

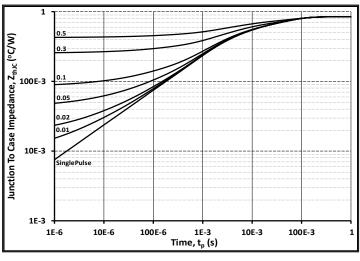


Figure 21. Transient Thermal Impedance (Junction - Case)

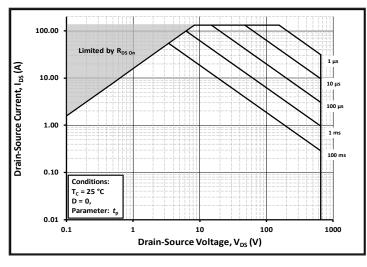


Figure 22. Safe Operating Area

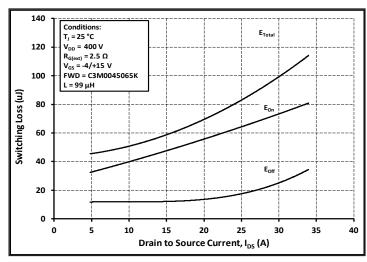


Figure 23. Clamped Inductive Switching Energy vs. Drain Current (V_{DD} = 400V)

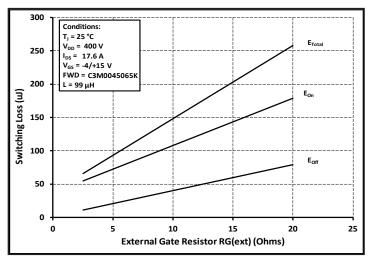


Figure 24. Clamped Inductive Switching Energy vs. $R_{\rm G(ext)}$



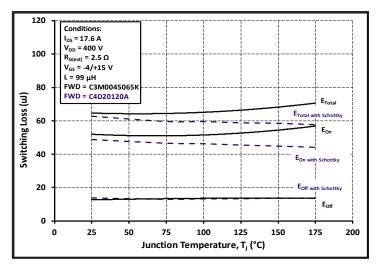


Figure 25. Clamped Inductive Switching Energy vs.
Temperature

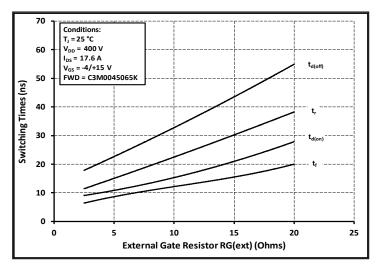


Figure 26. Switching Times vs. $R_{\rm G(ext)}$



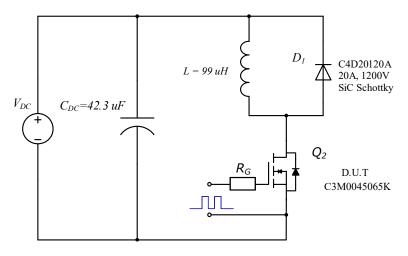


Figure 27. Clamped Inductive Switching Waveform Test Circuit

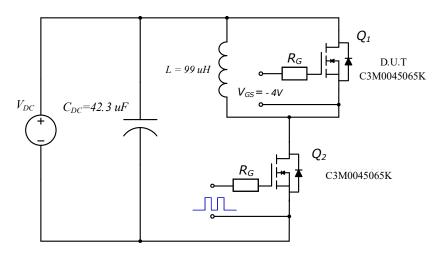


Figure 28. Body Diode Recovery Test Circuit

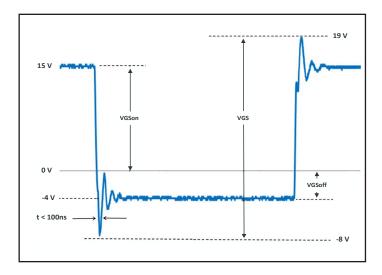
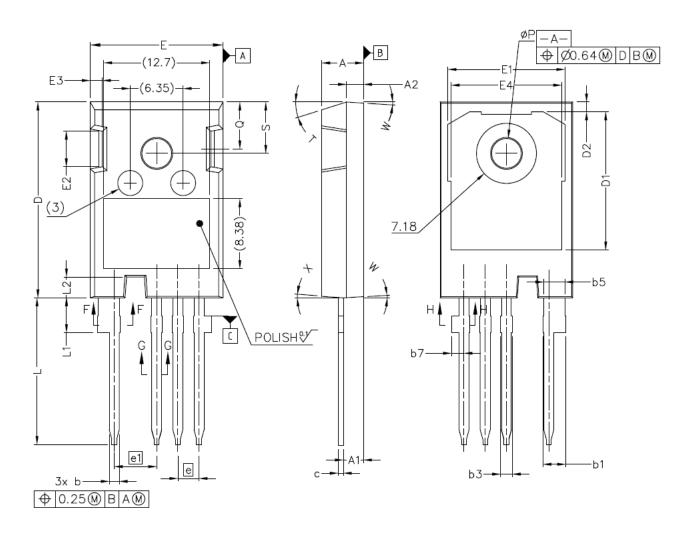


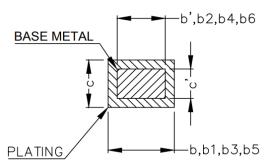
Figure 29. $V_{\rm GS}$ Waveform Example



Package Dimensions

Package TO-247-4L





SECTION "F-F", "G-G" AND "H-H" SCALE: NONE



Package Dimensions

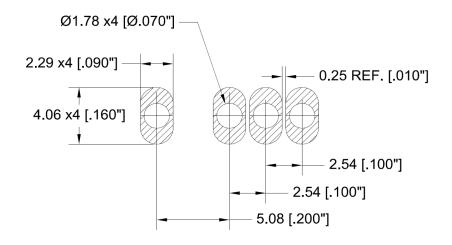
Package TO-247-4L

NOTE;

- 1. ALL METAL SURFACES: TIN PLATED, EXCEPT AREA OF CUT
- 2. DIMENSIONING & TOLERANCEING CONFIRM TO ASME Y14.5M-1994.
- 3. ALL DIMENSIONS ARE IN MILLIMETERS. ANGLES ARE IN DEGREES.
- 4. 'N' IS THE NUMBER OF TERMINAL POSITIONS

	N 411 1 1 N	ACTERC				
SYM	MILLIMETERS					
	MIN	MAX				
Α	4.83	5.21				
A1	2.29	2.54				
A2	1.91	2.16				
b`	1.07	1.28				
b	1.07	1.33				
b1	2.39	2.94				
b2	2.39	2.84				
b3	1.07	1.60				
b4	1.07	1.50				
b5	2.39	2.69				
b6	2.39	2.64				
b7	1.30	1.70				
c`	0.55	0.65				
С	0.55	0.68				
D	23.30	23.60				
D1	16.25	17.65				
D2	0.95	1.25				
E	15.75	16.13				

MILLIMETERS				
MIN	MAX			
13.10	14.15			
3.68	5.10			
1.00	1.90			
12.38	13.43			
2.54 BSC				
5.08 BSC				
4				
17.31	17.82			
3.97	4.37			
2.35	2.65			
3.51	3.65			
5.49	6.00			
6.04 6.30				
17.5° REF.				
3.5° REF.				
4° REF.				
	MIN 13.10 3.68 1.00 12.38 2.54 5.08 17.31 3.97 2.35 3.51 5.49 6.04 17.5° 3.5°			





Notes

RoHS Compliance

The levels of RoHS restricted materials in this product are below the maximum concentration values (also referred to as the threshold limits) permitted for such substances, or are used in an exempted application, in accordance with EU Directive 2011/65/EC (RoHS2), as implemented January 2, 2013. RoHS Declarations for this product can be obtained from your Cree representative or from the Product Documentation sections of www.cree.com.

REACh Compliance

REACh substances of high concern (SVHCs) information is available for this product. Since the European Chemical Agency (ECHA) has published notice of their intent to frequently revise the SVHC listing for the foreseeable future, please contact a Cree representative to insure you get the most up-to-date REACh SVHC Declaration. REACh banned substance information (REACh Article 67) is also available upon request.

This product has not been designed or tested for use in, and is not intended for use in, applications implanted into the human body
nor in applications in which failure of the product could lead to death, personal injury or property damage, including but not limited
to equipment used in the operation of nuclear facilities, life-support machines, cardiac defibrillators or similar emergency medical
equipment, aircraft navigation or communication or control systems, air traffic control systems.

Related Links

- SPICE Models: http://wolfspeed.com/power/tools-and-support
- SiC MOSFET Isolated Gate Driver reference design: http://wolfspeed.com/power/tools-and-support
- SiC MOSFET Evaluation Board: http://wolfspeed.com/power/tools-and-support